Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/633,609	BRUHN ET AL.	
Examiner	Art Unit	
Jerry Lin	1631	

SEARCHED						
Class	Subclass	Date	Examiner			
702	19	9/11/2006	JL			

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
	1					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST, Google Scholar: microarray, clevaed, probe, subarray, memory, pattern	9/11/2006	JL		
Inventor Search	9/11/2006	JL		
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